•	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/728,108	CHOU ET AL.	
Examiner	Art Unit	
Anthony Fick	1753	

SEARCHED			
Class	Subclass	Date	Examiner
136	253	6/13/2007	ADF
Vydated	previous	12/11/07	JTB
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEAR	CH STRATEGY	<u>') </u>
	DATE	EXMR
See EAST search history	6/13/2007	ADF
Inventor search	6/12/2007	ADF
Consulted with Nam Nguyen	6/13/2007	ADF